

<b>Notice of References Cited</b>			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/045,237	KIM, JONG-SUN	
			Examiner	Art Unit	Page 1 of 1
			Hai L. Nguyen	2816	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,735,669	05-2004	Shin, Dong Woo	711/106
X	B	US-6,654,900	11-2003	Cave, Michael D	713/501
X	C	US-6,525,581	02-2003	Choi, Young Bae	327/175
X	D	US-6,466,071	10-2002	Kim et al.	327/175
X	E	US-6,452,432	09-2002	Kim, Kyu-hyoun	327/158
X	F	US-6,448,828	09-2002	Stark et al.	327/175
X	G	US-6,342,801	01-2002	Shin, Dong Woo	327/175
X	H	US-6,211,722	04-2001	Mattia et al.	327/407
X	I	US-5,912,574	06-1999	Bhagwan, Raghunand	327/157
X	J	US-5,911,063	06-1999	Allen et al.	713/500
X	K	US-5,764,091	06-1998	Sumita et al.	327/175
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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